

SPM (Scanning Probe Microscope)

Desktop SPM with full automation

STM / AFM

Leading Innovation>>>

*Experiencing Nanocosm
Just a few mouse clicks*

Scanning Probe Microscope

SPM YOU NEED



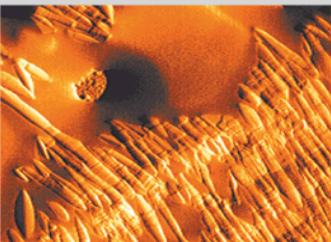
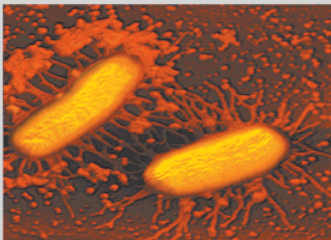
Model: Solver-Next



Scanning Probe Microscope

- Scanner type : Scan by sample
- Measuring heads : AFM and STM (Built-in, auto interchangeable)
- Sample dimensions : Up to 20 mm in diameter, up to 10 mm in height
- Sample weight : Up to 100 g
- XY sample positioning : 5x5 mm, motorized, Video monitored
- Min, XY sample position step: 0.15 μm
- Scanning field : 100x100x10 μm with closed-loop 3x3x2 μm in the low voltage mode
- Noise level Z : 0.03 nm (typically), 0.04 nm (max) with closed-loop sensors 0.02 nm in low voltage mode

Automated Scanning probe microscope



Features:

- Automated exchange of AFM and STM heads
- Automated alignment of optical feedback geometry (cantilever-laser-photodiode)
- Motorized software driven sample positioning
- Motorized focus and zoom of optical view
- Motorized positioning of the optical sample view
- Motorized enclosure door for improved isolation
- Automated software driven control of measurement modes

Performance capabilities:

- All basic Atomic Force Microscope techniques-- Topography, Phase imaging, Measurement of electric properties, nanolithography and more
- Scanning Tunneling Microscopy
- Wide range of operating conditions for experimentation -- in air or liquid
- **Ambient mode:** STM/AFM (contact + semicontact + non-contact) / Lateral Force Microscope / Phase Imaging / Force Modulation / Fore Spectroscopy / Adhesion Force Imaging, MFM / EFM / SCM / Kelvin Probe Microscope / Spreading Resistance Imaging / Nanoindentation / Lithography: AFM (Voltage + Force)
- **Ambient and liquid modes:** AFM (contact + semicontact + non-contact) / Lateral Force Microscope / Phase Imaging / Force Modulation / Adhesion Force Imaging / Force - Spectroscopy Lithography: AFM (Force)
- Low-noise capacitive closes-loop feedback in all three direction (XYZ) provides precision Nanometrology
- Atomic resolution



Product by NT-MDT

FC CE

www.isscope.com